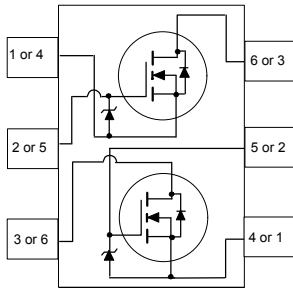


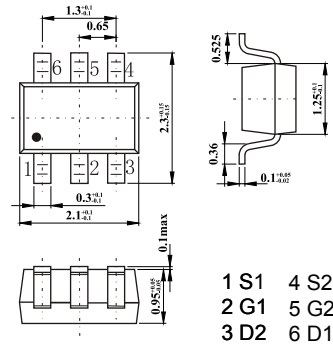
■ Features

- $V_{DS} (V) = 25V$
- $I_D = 220m A (V_{GS} = 4.5V)$
- $R_{DS(ON)} < 4 \Omega (V_{GS} = 4.5V)$
- $R_{DS(ON)} < 5 \Omega (V_{GS} = 2.7V)$
- Gate-Source Zener for ESD ruggedness (>6kV Human Body Model).



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Unit: mm



■ Absolute Maximum Ratings $T_a = 25^\circ C$

Parameter	Symbol	Rating	Unit	
Drain-Source Voltage	V_{DS}	25	V	
Gate-Source Voltage	V_{GS}	± 8		
Continuous Drain Current	I_D	Continuous	220	mA
		Pulsed	650	
Electrostatic Discharge Rating MIL-STD-883D Human Body Model(100 pF / 1500 W)	ESD	6	KV	
Power Dissipation	P_D	300	mW	
Thermal Resistance.Junction- to-Ambient	R_{thJA}	415	$^\circ C/W$	
Junction Temperature	T_J	150	$^\circ C$	
Storage Temperature Range	T_{stg}	-55 to 150		

■ Electrical Characteristics Ta = 25°C

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V _{DSS}	I _D =250 μA, V _{GS} =0V	25			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =20V, V _{GS} =0V			1	μA
		V _{DS} =20V, V _{GS} =0V, T _J =55°C			10	
Gate-Body Leakage Current	I _{GSS}	V _{DS} =0V, V _{GS} =±8V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250 μA	0.65	0.85	1.5	V
Static Drain-Source On-Resistance	R _{DS(on)}	V _{GS} =4.5V, I _D =220mA		2.6	4	Ω
		V _{GS} =4.5V, I _D =220mA, T _J =125°C		5.3	7	
		V _{GS} =2.7V, I _D =190mA		3.7	5	
On State Drain Current	I _{D(ON)}	V _{GS} =4.5V, V _{DS} =5V	0.22			A
Forward Transconductance	g _{FS}	V _{DS} =5V, I _D =220mA		0.2		S
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =10V, f=1MHz		9.5		pF
Output Capacitance	C _{oss}			6		
Reverse Transfer Capacitance	C _{rss}			1.3		
Total Gate Charge	Q _g	V _{GS} =4.5V, V _{DS} =5V, I _D =220mA		0.29	0.4	nC
Gate Source Charge	Q _{gs}			0.12		
Gate Drain Charge	Q _{gd}			0.03		
Turn-On DelayTime	t _{d(on)}	V _{GS} =4.5V, V _{DS} =5V, I _D =500mA, R _G =50 Ω		5	10	ns
Turn-On Rise Time	t _r			4.5	10	
Turn-Off DelayTime	t _{d(off)}			4	8	
Turn-Off Fall Time	t _f			3.2	7	
Maximum Body-Diode Continuous Current	I _S				0.25	A
Diode Forward Voltage	V _{SD}	I _S =250mA, V _{GS} =0V (Note.1)		0.8	1.2	V

Note.1:Pulse Test: Pulse Width < 300μs, Duty Cycle < 2.0%.

Typical Characteristics

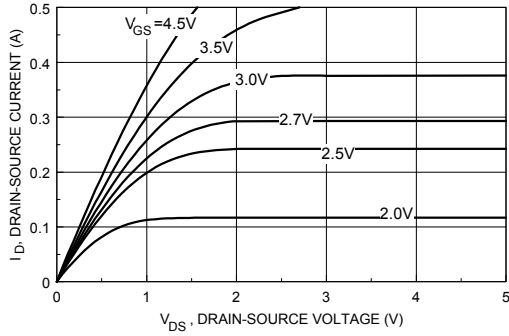


Figure 1. On-Region Characteristics.

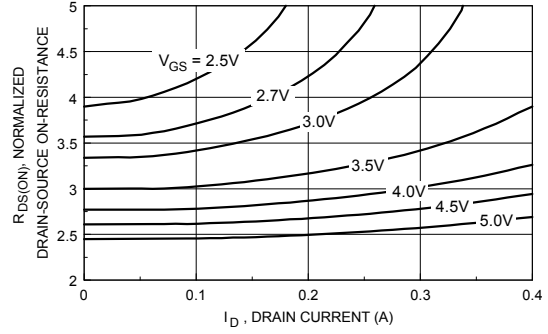


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

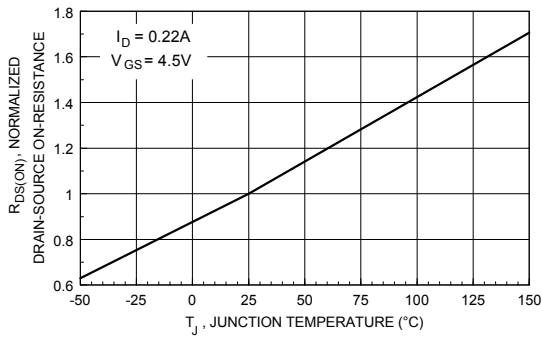


Figure 3. On-Resistance Variation with Temperature.

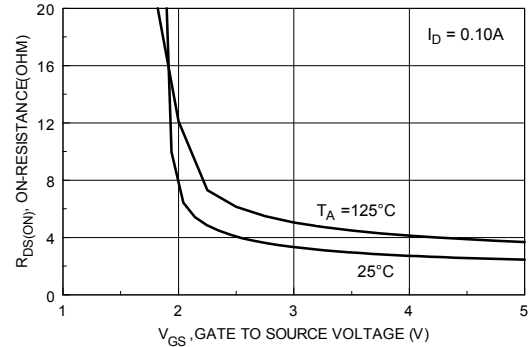


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

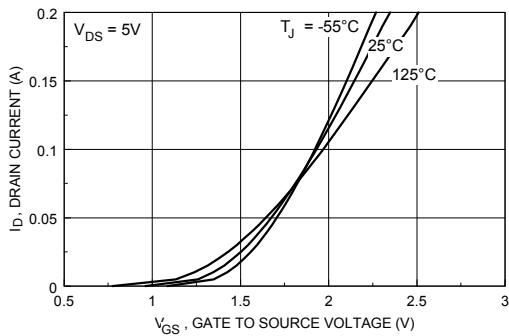


Figure 5. Transfer Characteristics.

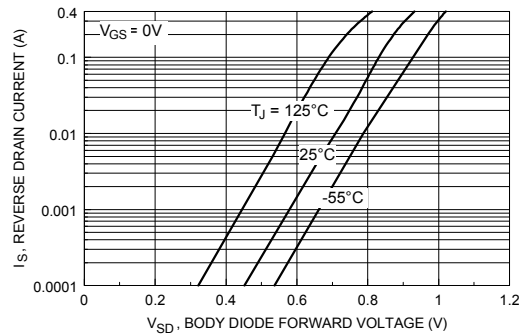


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics

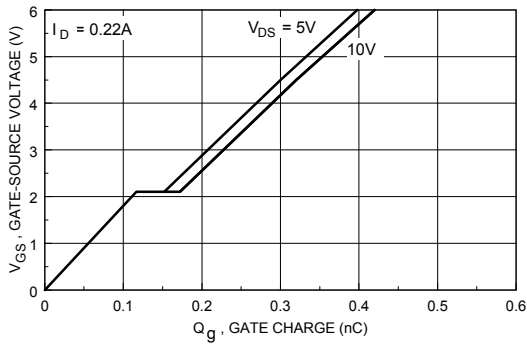


Figure 7. Gate Charge Characteristics.

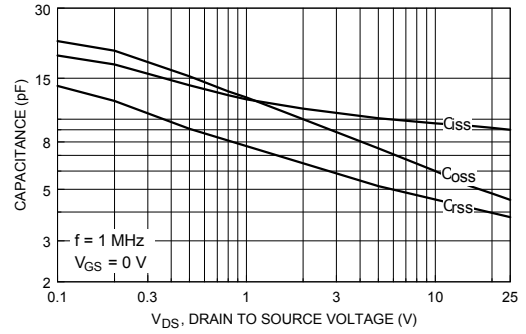


Figure 8. Capacitance Characteristics .

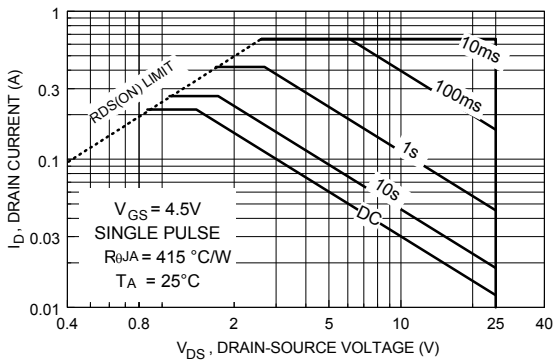


Figure 9. Maximum Safe Operating Area.

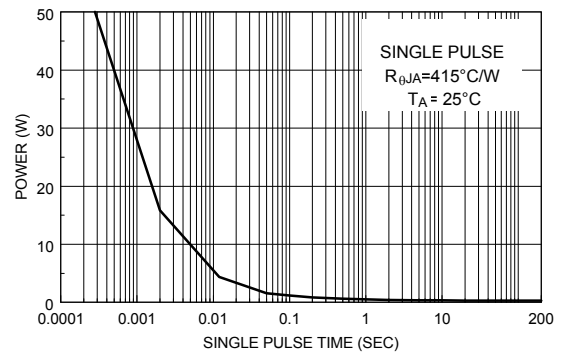


Figure 10. Single Pulse Maximum Power Dissipation.

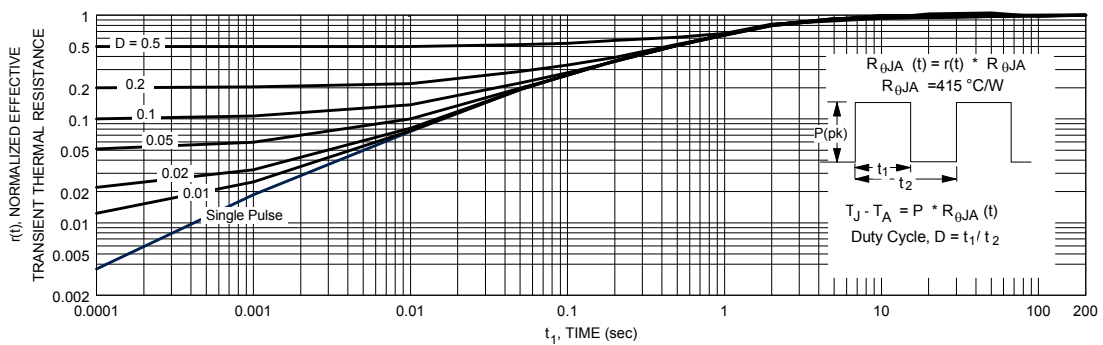


Figure 11. Transient Thermal Response Curve .

Thermal characterization performed using the conditions described in note 1.
Transient thermal response will change depending on the circuit board design.